

IN THE SPECIFICATION:

Paragraph beginning at line 13 of page 9 has been amended as follows:

Fig. 8(a) 8 is a schematic diagram illustrating a sample in which a cross section is formed by a focused ion beam while the cross section is rotated to different positions with respect to the irradiating direction of the focused ion beam, and Fig. 8(b) is a schematic diagram illustrating the sample in which streaks are formed on the cross section by the focused ion beam;